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Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	14151
Number of Logic Elements/Cells	300000
Total RAM Bits	17358848
Number of I/O	544
Number of Gates	-
Voltage - Supply	1.07V ~ 1.13V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1152-BBGA, FCBGA Exposed Pad
Supplier Device Package	1152-FBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5agxmb1g6f35c6n

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This datasheet describes the electrical characteristics, switching characteristics, configuration specifications, and I/O timing for Arria® V devices.

Arria V devices are offered in commercial and industrial grades. Commercial devices are offered in –C4 (fastest), –C5, and –C6 speed grades. Industrial grade devices are offered in the –I3 and –I5 speed grades.

Related Information

[Arria V Device Overview](#)

Provides more information about the densities and packages of devices in the Arria V family.

Electrical Characteristics

The following sections describe the operating conditions and power consumption of Arria V devices.

Operating Conditions

Arria V devices are rated according to a set of defined parameters. To maintain the highest possible performance and reliability of the Arria V devices, you must consider the operating requirements described in this section.

Absolute Maximum Ratings

This section defines the maximum operating conditions for Arria V devices. The values are based on experiments conducted with the devices and theoretical modeling of breakdown and damage mechanisms.

The functional operation of the device is not implied for these conditions.

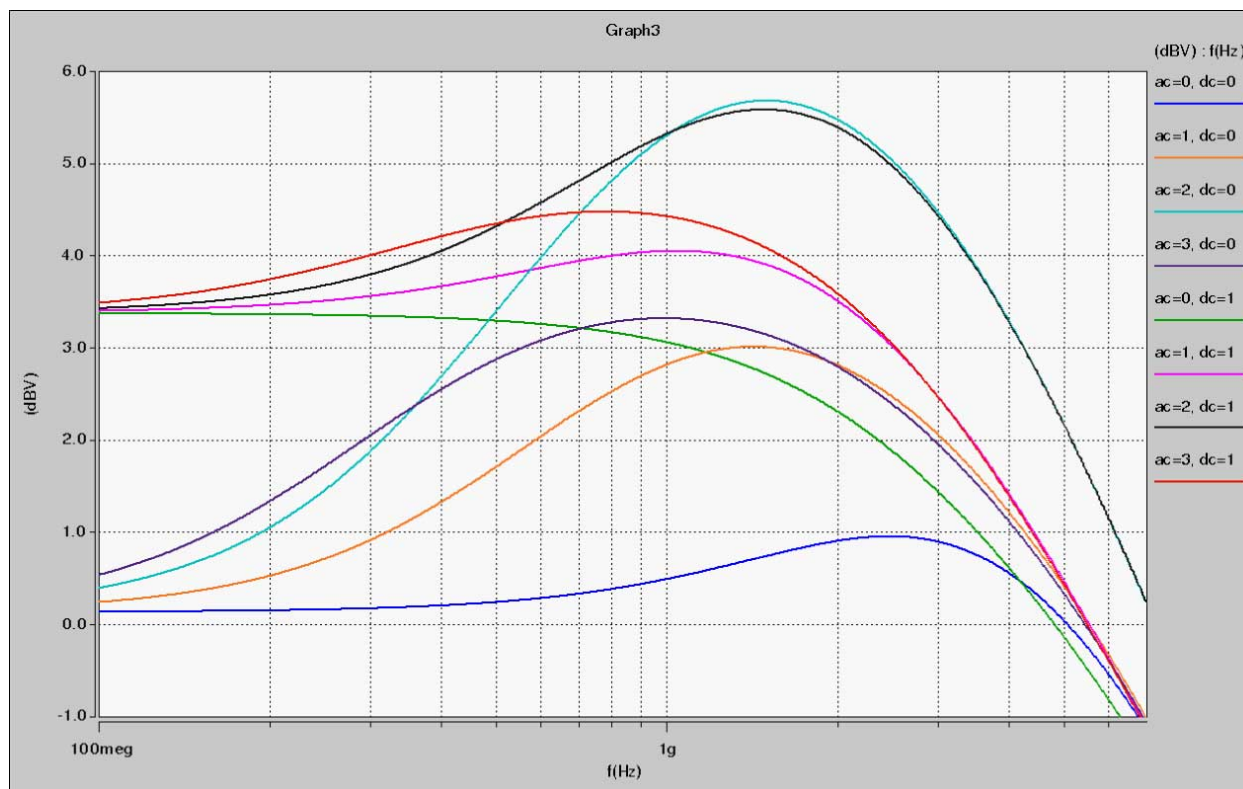
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CTLE Response at Data Rates ≤ 3.25 Gbps across Supported AC Gain and DC Gain

Figure 1-3: CTLE Response at Data Rates ≤ 3.25 Gbps across Supported AC Gain and DC Gain for Arria V GX, GT, SX, and ST Devices



Typical TX V_{OD} Setting for Arria V Transceiver Channels with termination of 100 Ω Table 1-32: Typical TX V_{OD} Setting for Arria V Transceiver Channels with termination of 100 Ω

Symbol	V_{OD} Setting ⁽⁵⁸⁾	V_{OD} Value (mV)	V_{OD} Setting ⁽⁵⁸⁾	V_{OD} Value (mV)
V_{OD} differential peak-to-peak typical	6 ⁽⁵⁹⁾	120	34	680
	7 ⁽⁵⁹⁾	140	35	700
	8 ⁽⁵⁹⁾	160	36	720
	9	180	37	740
	10	200	38	760
	11	220	39	780
	12	240	40	800
	13	260	41	820
	14	280	42	840
	15	300	43	860
	16	320	44	880
	17	340	45	900
	18	360	46	920
	19	380	47	940
	20	400	48	960
	21	420	49	980
	22	440	50	1000
	23	460	51	1020
	24	480	52	1040

⁽⁵⁸⁾ Convert these values to their binary equivalent form if you are using the dynamic reconfiguration mode for PMA analog controls.⁽⁵⁹⁾ Only valid for data rates ≤ 5 Gbps.

Symbol		Condition	-I3, -C4			-I5, -C5			-C6			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
	TCCS	True Differential I/O Standards	—	—	150	—	—	150	—	—	150	ps
		Emulated Differential I/O Standards	—	—	300	—	—	300	—	—	300	ps
Receiver	True Differential I/O Standards - f_{HSDRDPA} (data rate)	SERDES factor J = 3 to 10 ⁽⁷⁶⁾	150	—	1250	150	—	1250	150	—	1050	Mbps
		SERDES factor J ≥ 8 with DPA ⁽⁷⁶⁾⁽⁷⁸⁾	150	—	1600	150	—	1500	150	—	1250	Mbps
	f_{HSDR} (data rate)	SERDES factor J = 3 to 10	⁽⁷⁷⁾	—	⁽⁸³⁾	⁽⁷⁷⁾	—	⁽⁸³⁾	⁽⁷⁷⁾	—	⁽⁸³⁾	Mbps
		SERDES factor J = 1 to 2, uses DDR registers	⁽⁷⁷⁾	—	⁽⁷⁹⁾	⁽⁷⁷⁾	—	⁽⁷⁹⁾	⁽⁷⁷⁾	—	⁽⁷⁹⁾	Mbps
DPA Mode	DPA run length	—	—	—	10000	—	—	10000	—	—	10000	UI
Soft-CDR Mode	Soft-CDR ppm tolerance	—	—	—	300	—	—	300	—	—	300	±ppm
Non-DPA Mode	Sampling Window	—	—	—	300	—	—	300	—	—	300	ps

⁽⁸³⁾ You can estimate the achievable maximum data rate for non-DPA mode by performing link timing closure analysis. You must consider the board skew margin, transmitter delay margin, and receiver sampling margin to determine the maximum data rate supported.

Memory Output Clock Jitter Specifications

Table 1-45: Memory Output Clock Jitter Specifications for Arria V Devices

The memory output clock jitter measurements are for 200 consecutive clock cycles, as specified in the JEDEC DDR2/DDR3 SDRAM standard.

The memory output clock jitter is applicable when an input jitter of 30 ps (p-p) is applied with bit error rate (BER) 10^{-12} , equivalent to 14 sigma.

Altera recommends using the UniPHY intellectual property (IP) with PHYCLK connections for better jitter performance.

Parameter	Clock Network	Symbol	-I3, -C4		-I5, -C5		-C6		Unit
			Min	Max	Min	Max	Min	Max	
Clock period jitter	PHYCLK	$t_{JIT(per)}$	-41	41	-50	50	-55	55	ps
Cycle-to-cycle period jitter	PHYCLK	$t_{JIT(cc)}$	63		90		94		ps

OCT Calibration Block Specifications

Table 1-46: OCT Calibration Block Specifications for Arria V Devices

Symbol	Description	Min	Typ	Max	Unit
OCTUSRCLK	Clock required by OCT calibration blocks	—	—	20	MHz
T_{OCTCAL}	Number of OCTUSRCLK clock cycles required for R_S OCT/ R_T OCT calibration	—	1000	—	Cycles
$T_{OCTSHIFT}$	Number of OCTUSRCLK clock cycles required for OCT code to shift out	—	32	—	Cycles
T_{RS_RT}	Time required between the <code>dyn_term_ctrl</code> and <code>oe</code> signal transitions in a bidirectional I/O buffer to dynamically switch between R_S OCT and R_T OCT	—	2.5	—	ns

HPS PLL Input Jitter

Use the following equation to determine the maximum input jitter (peak-to-peak) the HPS PLLs can tolerate. The divide value (N) is the value programmed into the denominator field of the VCO register for each PLL. The PLL input reference clock is divided by this value. The range of the denominator is 1 to 64.

$$\text{Maximum input jitter} = \text{Input clock period} \times \text{Divide value (N)} \times 0.02$$

Table 1-50: Examples of Maximum Input Jitter

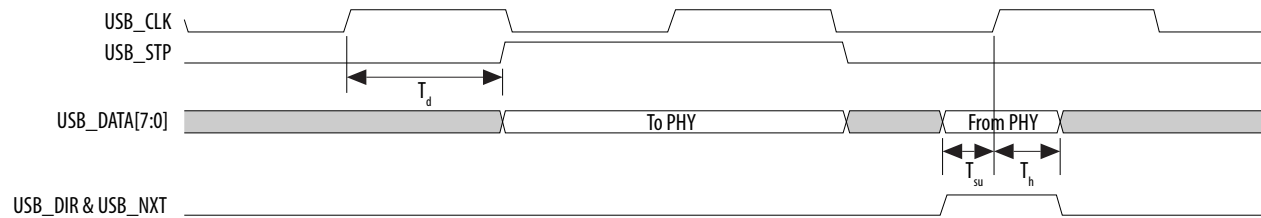
Input Reference Clock Period	Divide Value (N)	Maximum Jitter	Unit
40 ns	1	0.8	ns
40 ns	2	1.6	ns
40 ns	4	3.2	ns

Quad SPI Flash Timing Characteristics

Table 1-51: Quad Serial Peripheral Interface (SPI) Flash Timing Requirements for Arria V Devices

Symbol	Description	Min	Typ	Max	Unit
F _{clk}	SCLK_OUT clock frequency (External clock)	—	—	108	MHz
T _{qspi_clk}	QSPI_CLK clock period (Internal reference clock)	2.32	—	—	ns
T _{dutycycle}	SCLK_OUT duty cycle	45	—	55	%
T _{dssfst}	Output delay QSPI_SS valid before first clock edge	—	1/2 cycle of SCLK_OUT	—	ns
T _{dsslst}	Output delay QSPI_SS valid after last clock edge	–1	—	1	ns
T _{dio}	I/O data output delay	–1	—	1	ns
T _{din_start}	Input data valid start	—	—	$(2 + R_{\text{delay}}) \times T_{\text{qspi_clk}} - 7.52^{(85)}$	ns

Figure 1-12: USB Timing Diagram

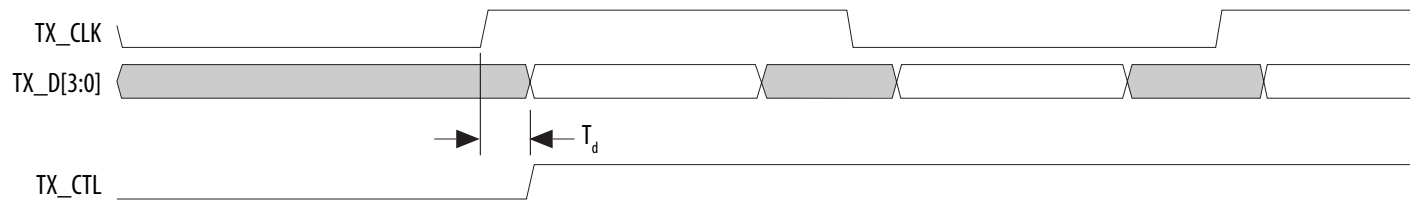


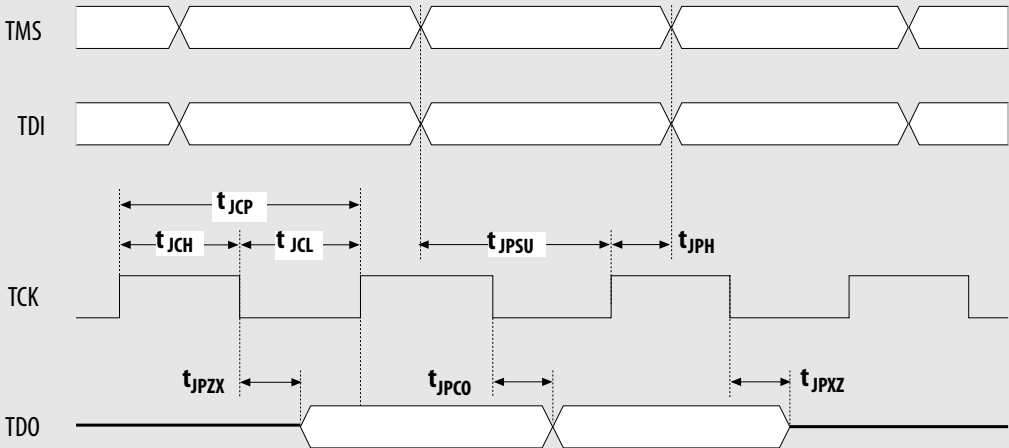
Ethernet Media Access Controller (EMAC) Timing Characteristics

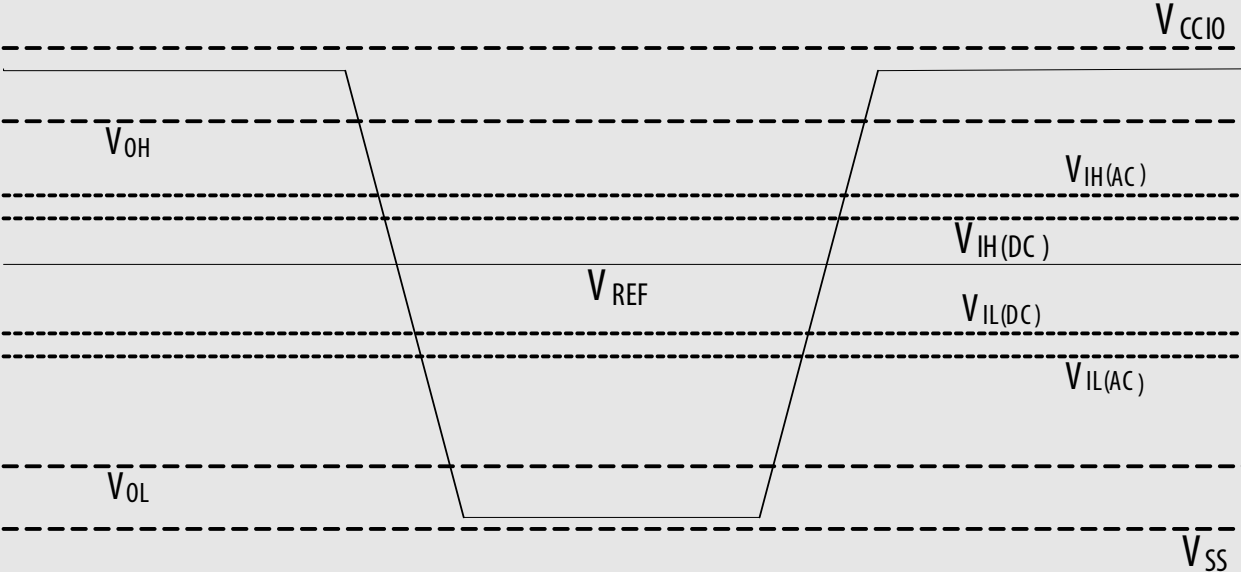
Table 1-56: Reduced Gigabit Media Independent Interface (RGMII) TX Timing Requirements for Arria V Devices

Symbol	Description	Min	Typ	Max	Unit
T_{clk} (1000Base-T)	TX_CLK clock period	—	8	—	ns
T_{clk} (100Base-T)	TX_CLK clock period	—	40	—	ns
T_{clk} (10Base-T)	TX_CLK clock period	—	400	—	ns
$T_{duty cycle}$	TX_CLK duty cycle	45	—	55	%
T_d	TX_CLK to TXD/TX_CTL output data delay	-0.85	—	0.15	ns

Figure 1-13: RGMII TX Timing Diagram



Term	Definition
JTAG timing specifications	<p data-bbox="669 207 995 240">JTAG Timing Specifications</p>  <p>The diagram illustrates the JTAG timing specifications for four signals: TMS, TDI, TCK, and TDO. TMS and TDI are shown as high-impedance inputs with a pull-up resistor. TCK is a clock signal. TDO is an output signal with a pull-up resistor. The timing parameters are defined as follows:</p> <ul style="list-style-type: none"> t_{JCP}: Time from TCK rising edge to TMS rising edge. t_{JCH}: Time from TCK rising edge to TDI rising edge. t_{JCL}: Time from TCK rising edge to TDI falling edge. t_{JPSU}: Time from TCK rising edge to TDO rising edge. t_{JPH}: Time from TCK rising edge to TDO falling edge. t_{JPZX}: Time from TCK rising edge to TDO rising edge. t_{JPCO}: Time from TCK rising edge to TDO falling edge. t_{JPXZ}: Time from TCK rising edge to TDO rising edge.

Term	Definition
Single-ended voltage referenced I/O standard	<p>The JEDEC standard for the SSTL and HSTL I/O defines both the AC and DC input signal values. The AC values indicate the voltage levels at which the receiver must meet its timing specifications. The DC values indicate the voltage levels at which the final logic state of the receiver is unambiguously defined. After the receiver input has crossed the AC value, the receiver changes to the new logic state.</p> <p>The new logic state is then maintained as long as the input stays beyond the DC threshold. This approach is intended to provide predictable receiver timing in the presence of input waveform ringing.</p> <p>Single-Ended Voltage Referenced I/O Standard</p> 
t_C	High-speed receiver/transmitter input and output clock period.
TCCS (channel-to-channel-skew)	The timing difference between the fastest and slowest output edges, including the t_{CO} variation and clock skew, across channels driven by the same PLL. The clock is included in the TCCS measurement (refer to the Timing Diagram figure under SW in this table).
t_{DUTY}	High-speed I/O block—Duty cycle on high-speed transmitter output clock.

Bus Hold Specifications

Table 2-9: Bus Hold Parameters for Arria V GZ Devices

Parameter	Symbol	Conditions	V _{CCIO}										Unit
			1.2 V		1.5 V		1.8 V		2.5 V		3.0 V		
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Low sustaining current	I _{SUSL}	V _{IN} > V _{IL} (maximum)	22.5	—	25.0	—	30.0	—	50.0	—	70.0	—	μA
High sustaining current	I _{SUSH}	V _{IN} < V _{IH} (minimum)	−22.5	—	−25.0	—	−30.0	—	−50.0	—	−70.0	—	μA
Low overdrive current	I _{ODL}	0V < V _{IN} < V _{CCIO}	—	120	—	160	—	200	—	300	—	500	μA
High overdrive current	I _{ODH}	0V < V _{IN} < V _{CCIO}	—	−120	—	−160	—	−200	—	−300	—	−500	μA
Bus-hold trip point	V _{TRIP}	—	0.45	0.95	0.50	1.00	0.68	1.07	0.70	1.70	0.80	2.00	V

On-Chip Termination (OCT) Specifications

If you enable OCT calibration, calibration is automatically performed at power-up for I/Os connected to the calibration block.

Table 2-10: OCT Calibration Accuracy Specifications for Arria V GZ Devices

OCT calibration accuracy is valid at the time of calibration only.

Symbol	Description	V _{CCIO} (V)	Typical	Unit
dR/dV	OCT variation with voltage without re-calibration	3.0	0.0297	%/mV
		2.5	0.0344	
		1.8	0.0499	
		1.5	0.0744	
		1.2	0.1241	
dR/dT	OCT variation with temperature without re-calibration	3.0	0.189	%/°C
		2.5	0.208	
		1.8	0.266	
		1.5	0.273	
		1.2	0.317	

Pin Capacitance

Table 2-13: Pin Capacitance for Arria V GZ Devices

Symbol	Description	Maximum	Unit
C _{IOTB}	Input capacitance on the top and bottom I/O pins	6	pF
C _{IOLR}	Input capacitance on the left and right I/O pins	6	pF
C _{OUTFB}	Input capacitance on dual-purpose clock output and feedback pins	6	pF

Hot Socketing

Table 2-14: Hot Socketing Specifications for Arria V GZ Devices

Symbol	Description	Maximum
$I_{IOPIN} (DC)$	DC current per I/O pin	300 μA
$I_{IOPIN} (AC)$	AC current per I/O pin	8 mA ⁽¹²⁴⁾
$I_{XCVR-TX} (DC)$	DC current per transceiver transmitter pin	100 mA
$I_{XCVR-RX} (DC)$	DC current per transceiver receiver pin	50 mA

Internal Weak Pull-Up Resistor

Table 2-15: Internal Weak Pull-Up Resistor for Arria V GZ Devices

All I/O pins have an option to enable the weak pull-up resistor except the configuration, test, and JTAG pins. The internal weak pull-down feature is only available for the JTAG TCK pin. The typical value for this internal weak pull-down resistor is approximately 25 k Ω .

Symbol	Description	V_{CCIO} Conditions (V) ⁽¹²⁵⁾	Value ⁽¹²⁶⁾	Unit
R_{PU}	Value of the I/O pin pull-up resistor before and during configuration, as well as user mode if you enable the programmable pull-up resistor option.	3.0 $\pm 5\%$	25	k Ω
		2.5 $\pm 5\%$	25	k Ω
		1.8 $\pm 5\%$	25	k Ω
		1.5 $\pm 5\%$	25	k Ω
		1.35 $\pm 5\%$	25	k Ω
		1.25 $\pm 5\%$	25	k Ω
		1.2 $\pm 5\%$	25	k Ω

⁽¹²⁴⁾ The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns, $|I_{IOPIN}| = C dv/dt$, in which C is the I/O pin capacitance and dv/dt is the slew rate.

⁽¹²⁵⁾ The pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO} .

⁽¹²⁶⁾ These specifications are valid with a $\pm 10\%$ tolerance to cover changes over PVT.

I/O Standard Specifications

The V_{OL} and V_{OH} values are valid at the corresponding I_{OH} and I_{OL} , respectively.

Table 2-16: Single-Ended I/O Standards for Arria V GZ Devices

I/O Standard	V_{CCIO} (V)			V_{IL} (V)		V_{IH} (V)		V_{OL} (V)	V_{OH} (V)	I_{OL} (mA)	I_{OH} (mA)
	Min	Typ	Max	Min	Max	Min	Max	Max	Min		
LVTTL	2.85	3	3.15	-0.3	0.8	1.7	3.6	0.4	2.4	2	-2
LVC MOS	2.85	3	3.15	-0.3	0.8	1.7	3.6	0.2	$V_{CCIO} - 0.2$	0.1	-0.1
2.5 V	2.375	2.5	2.625	-0.3	0.7	1.7	3.6	0.4	2	1	-1
1.8 V	1.71	1.8	1.89	-0.3	$0.35 \times V_{CCIO}$	$0.65 \times V_{CCIO}$	$V_{CCIO} + 0.3$	0.45	$V_{CCIO} - 0.45$	2	-2
1.5 V	1.425	1.5	1.575	-0.3	$0.35 \times V_{CCIO}$	$0.65 \times V_{CCIO}$	$V_{CCIO} + 0.3$	$0.25 \times V_{CCIO}$	$0.75 \times V_{CCIO}$	2	-2
1.2 V	1.14	1.2	1.26	-0.3	$0.35 \times V_{CCIO}$	$0.65 \times V_{CCIO}$	$V_{CCIO} + 0.3$	$0.25 \times V_{CCIO}$	$0.75 \times V_{CCIO}$	2	-2

Table 2-17: Single-Ended SSTL, HSTL, and HSUL I/O Reference Voltage Specifications for Arria V GZ Devices

I/O Standard	V_{CCIO} (V)			V_{REF} (V)			V_{TT} (V)		
	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max
SSTL-2 Class I, II	2.375	2.5	2.625	$0.49 \times V_{CCIO}$	$0.5 \times V_{CCIO}$	$0.51 \times V_{CCIO}$	$V_{REF} - 0.04$	V_{REF}	$V_{REF} + 0.04$
SSTL-18 Class I, II	1.71	1.8	1.89	0.833	0.9	0.969	$V_{REF} - 0.04$	V_{REF}	$V_{REF} + 0.04$
SSTL-15 Class I, II	1.425	1.5	1.575	$0.49 \times V_{CCIO}$	$0.5 \times V_{CCIO}$	$0.51 \times V_{CCIO}$	$0.49 \times V_{CCIO}$	$0.5 \times V_{CCIO}$	$0.51 \times V_{CCIO}$

I/O Standard	V _{CCIO} (V)			V _{DIF(DC)} (V)		V _{X(AC)} (V)			V _{CM(DC)} (V)			V _{DIF(AC)} (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Typ	Max	Min	Max
HSTL-12 Class I, II	1.14	1.2	1.26	0.16	V _{CCIO} + 0.3	—	0.5 × V _{CCIO}	—	0.4 × V _{CCIO}	0.5 × V _{CCIO}	0.6 × V _{CCIO}	0.3	V _{CCIO} + 0.48
HSUL-12	1.14	1.2	1.3	0.26	0.26	0.5 × V _{CCIO} - 0.12	0.5 × V _{CCIO}	0.5 × V _{CCIO} + 0.12	0.4 × V _{CCIO}	0.5 × V _{CCIO}	0.6 × V _{CCIO}	0.44	0.44

Table 2-21: Differential I/O Standard Specifications for Arria V GZ Devices

I/O Standard	V _{CCIO} (V) ⁽¹²⁸⁾			V _{ID} (mV) ⁽¹²⁹⁾			V _{ICM(DC)} (V)			V _{OD} (V) ⁽¹³⁰⁾			V _{OCM} (V) ⁽¹³⁰⁾		
	Min	Typ	Max	Min	Condition	Max	Min	Condition	Max	Min	Typ	Max	Min	Typ	Max
PCML	Transmitter, receiver, and input reference clock pins of the high-speed transceivers use the PCML I/O standard. For transmitter, receiver, and reference clock I/O pin specifications, refer to the "Transceiver Performance Specifications" section.														
2.5 V LVDS ⁽¹³¹⁾	2.375	2.5	2.625	100	V _{CM} = 1.25 V	—	0.05	D _{MAX} ≤ 700 Mbps	1.8	0.247	—	0.6	1.125	1.25	1.375
						—	1.05	D _{MAX} > 700 Mbps	1.55	0.247	—	0.6	1.125	1.25	1.375
BLVDS ⁽¹³²⁾	2.375	2.5	2.625	100	—	—	—	—	—	—	—	—	—	—	—

⁽¹²⁸⁾ Differential inputs are powered by VCCPD which requires 2.5 V.

⁽¹²⁹⁾ The minimum V_{ID} value is applicable over the entire common mode range, V_{CM}.

⁽¹³⁰⁾ RL range: 90 ≤ RL ≤ 110 Ω.

⁽¹³¹⁾ For optimized LVDS receiver performance, the receiver voltage input range must be between 0.25 V to 1.6 V for data rates above 700 Mbps, and 0 V to 1.85 V for data rates below 700 Mbps.

⁽¹³²⁾ There are no fixed V_{ICM}, V_{OD}, and V_{OCM} specifications for BLVDS. They depend on the system topology.

I/O Standard	V_{CCIO} (V) ⁽¹²⁸⁾			V_{ID} (mV) ⁽¹²⁹⁾			$V_{ICM(DC)}$ (V)			V_{OD} (V) ⁽¹³⁰⁾			V_{OCM} (V) ⁽¹³⁰⁾		
	Min	Typ	Max	Min	Condition	Max	Min	Condition	Max	Min	Typ	Max	Min	Typ	Max
RSDS (HIO) ⁽¹³³⁾	2.375	2.5	2.625	100	$V_{CM} = 1.25$ V	—	0.3	—	1.4	0.1	0.2	0.6	0.5	1.2	1.4
Mini-LVDS (HIO) ⁽¹³⁴⁾	2.375	2.5	2.625	200	—	600	0.4	—	1.325	0.25	—	0.6	1	1.2	1.4
LVPECL ^{(135), (136)}	—	—	—	300	—	—	0.6	$D_{MAX} \leq 700$ Mbps	1.8	—	—	—	—	—	—
	—	—	—	300	—	—	1	$D_{MAX} > 700$ Mbps	1.6	—	—	—	—	—	—

Related Information[Glossary](#) on page 2-73⁽¹²⁸⁾ Differential inputs are powered by VCCPD which requires 2.5 V.⁽¹²⁹⁾ The minimum VID value is applicable over the entire common mode range, VCM.⁽¹³⁰⁾ RL range: $90 \leq RL \leq 110 \Omega$.⁽¹³³⁾ For optimized RSBS receiver performance, the receiver voltage input range must be between 0.25 V to 1.45 V.⁽¹³⁴⁾ For optimized Mini-LVDS receiver performance, the receiver voltage input range must be between 0.3 V to 1.425 V.⁽¹³⁵⁾ LVPECL is only supported on dedicated clock input pins.⁽¹³⁶⁾ For optimized LVPECL receiver performance, the receiver voltage input range must be between 0.85 V to 1.75 V for data rate above 700 Mbps and 0.45 V to 1.95 V for data rate below 700 Mbps.

Symbol/Description	Conditions	Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	
Maximum peak-to-peak differential input voltage V_{ID} (diff p-p) before device configuration	—	—	—	1.6	—	—	1.6	V
Maximum peak-to-peak differential input voltage V_{ID} (diff p-p) after device configuration ⁽¹⁴⁶⁾	$V_{CCR_GXB} = 1.0\text{ V}$ ($V_{ICM} = 0.75\text{ V}$)	—	—	1.8	—	—	1.8	V
	$V_{CCR_GXB} = 0.85\text{ V}$ ($V_{ICM} = 0.6\text{ V}$)	—	—	2.4	—	—	2.4	V
Minimum differential eye opening at receiver serial input pins ⁽¹⁴⁷⁾⁽¹⁴⁸⁾	—	85	—	—	85	—	—	mV
Differential on-chip termination resistors	85- Ω setting	—	$85 \pm 30\%$	—	—	$85 \pm 30\%$	—	Ω
	100- Ω setting	—	$100 \pm 30\%$	—	—	$100 \pm 30\%$	—	Ω
	120- Ω setting	—	$120 \pm 30\%$	—	—	$120 \pm 30\%$	—	Ω
	150- Ω setting	—	$150 \pm 30\%$	—	—	$150 \pm 30\%$	—	Ω

⁽¹⁴⁶⁾ The maximum peak to peak differential input voltage V_{ID} after device configuration is equal to $4 \times (\text{absolute } V_{MAX} \text{ for receiver pin} - V_{ICM})$.

⁽¹⁴⁷⁾ The differential eye opening specification at the receiver input pins assumes that **Receiver Equalization** is disabled. If you enable **Receiver Equalization**, the receiver circuitry can tolerate a lower minimum eye opening, depending on the equalization level.

⁽¹⁴⁸⁾ Minimum eye opening of 85 mV is only for the unstressed input eye condition.

Mode ⁽¹⁶⁴⁾	Transceiver Speed Grade	PMA Width	20	20	16	16	10	10	8	8
		PCS/Core Width	40	20	32	16	20	10	16	8
Register	2	C3, I3L core speed grade	9.9	9	7.92	7.2	4.9	4.5	3.92	3.6
	3	C4, I4 core speed grade	8.8	8.2	7.04	6.56	4.4	4.1	3.52	3.28

Related Information[Operating Conditions](#) on page 2-1**10G PCS Data Rate****Table 2-31: 10G PCS Approximate Maximum Data Rate (Gbps) for Arria V GZ Devices**

Mode ⁽¹⁶⁵⁾	Transceiver Speed Grade	PMA Width	64	40	40	40	32	32
		PCS Width	64	66/67	50	40	64/66/67	32
FIFO	2	C3, I3L core speed grade	12.5	12.5	10.69	12.5	10.88	10.88
	3	C4, I4 core speed grade	10.3125	10.3125	10.69	10.3125	9.92	9.92
Register	2	C3, I3L core speed grade	12.5	12.5	10.69	12.5	10.88	10.88
	3	C4, I4 core speed grade	10.3125	10.3125	10.69	10.3125	9.92	9.92

⁽¹⁶⁴⁾ The Phase Compensation FIFO can be configured in FIFO mode or register mode. In the FIFO mode, the pointers are not fixed, and the latency can vary. In the register mode the pointers are fixed for low latency.

⁽¹⁶⁵⁾ The Phase Compensation FIFO can be configured in FIFO mode or register mode. In the FIFO mode, the pointers are not fixed, and the latency can vary. In the register mode the pointers are fixed for low latency.

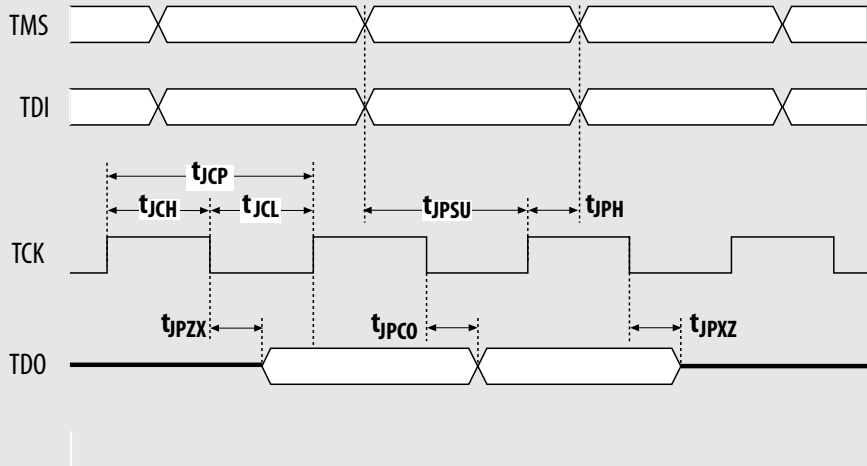
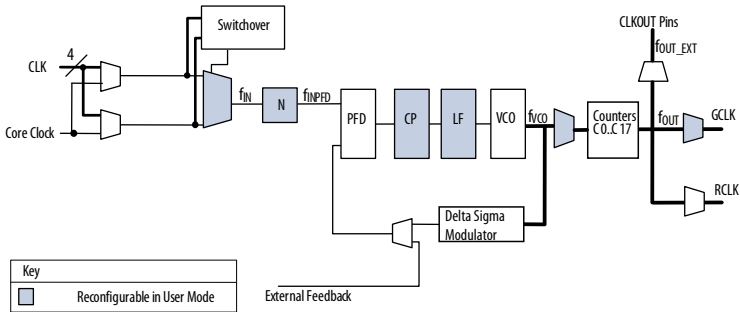
Symbol	Parameter	Min	Typ	Max	Unit
k_{VALUE}	Numerator of Fraction	128	8388608	2147483648	—
f_{RES}	Resolution of VCO frequency ($f_{\text{INPFD}} = 100 \text{ MHz}$)	390625	5.96	0.023	Hz

Related Information

- [Duty Cycle Distortion \(DCD\) Specifications](#) on page 2-56
- [DLL Range Specifications](#) on page 2-53

DSP Block Specifications**Table 2-35: DSP Block Performance Specifications for Arria V GZ Devices**

Mode	Performance			Unit
	C3, I3L	C4	I4	
Modes using One DSP Block				
Three 9×9	480	420		MHz
One 18×18	480	420	400	MHz
Two partial 18×18 (or 16×16)	480	420	400	MHz
One 27×27	400	350		MHz
One 36×18	400	350		MHz
One sum of two 18×18 (One sum of two 16×16)	400	350		MHz
One sum of square	400	350		MHz
One 18×18 plus $36(a \times b) + c$	400	350		MHz
Modes using Two DSP Blocks				
Three 18×18	400	350		MHz
One sum of four 18×18	380	300		MHz

Term	Definition
JTAG Timing Specifications	<p>JTAG Timing Specifications:</p>  <p>The diagram illustrates the timing relationships for JTAG signals. TMS and TDI are shown as high-impedance signals during certain phases. TCK is the clock signal. TDO is the data output signal. The timing parameters are defined as follows:</p> <ul style="list-style-type: none">t_{JCP}: JTAG Capture Setup timet_{JCH}: JTAG Capture Hold timet_{JCL}: JTAG Capture Latencyt_{JPSU}: JTAG Push Setup timet_{JPH}: JTAG Push Hold timet_{JPZX}: JTAG Push Z-bus timet_{JPCO}: JTAG Push Clock Offset timet_{JPXZ}: JTAG Push Z-bus time
PLL Specifications	<p>Diagram of PLL Specifications</p>  <p>The diagram shows the internal structure of a PLL. It starts with a Core Clock input, which is divided by 4 and then fed into a Switchover block. The output of the Switchover block is f_{IN}, which is then divided by N to produce f_{INPFD}. This signal is fed into a PFD (Phase-Frequency Detector) block, which is also connected to a CP (Charge Pump) block. The output of the CP block is fed into a LF (Loop Filter) block, which is also connected to a VCO (Voltage-Controlled Oscillator) block. The output of the VCO block is f_{VCO}, which is fed into a Counters block (CO, C 17). The output of the Counters block is f_{OUT}, which is then fed into a Delta Sigma Modulator block. The output of the Delta Sigma Modulator block is f_{OUT_EXT}, which is then fed into a GCLK block. The output of the GCLK block is RCLK. A feedback path is shown from the output of the Counters block back to the input of the PFD block, labeled External Feedback.</p> <p>Key</p> <ul style="list-style-type: none">Reconfigurable in User Mode <p>Note:</p> <ol style="list-style-type: none">Core Clock can only be fed by dedicated clock input pins or PLL outputs.